

1AP5 Rec'd PGT/PTO 28 MAR 2006

Sheet 1 of 1

Form PTO-1449 (REV. 1/06)		US Dept. of Commerce PATENT & TRADEMARK OFFICE		ATTY DOCKET NO. 127243		APPLICATION NO. New U.S. National Stage of PCT/JP2004/016793Pat ent Application	
INFORMATION DISCLOSURE STATEMENT (Use several sheets if necessary)				10/573788			
				APPLICANT(S) Toshifumi TAKAOKA et al.			
				FILING DATE March 28, 2006		GROUP	

U.S. PATENT DOCUMENTS				
Examiner Initials	Cite No.	Document Number	Date	Name
<div style="font-size: 2em;"> NK J V </div>	1	5,496,229	03/05/1996	MIYAMOTO
	2	5,481,461	01/02/1996	MIYAMOTO et al.
	3	6,244,242 B1	06/12/2001	GRIZZLE et al.
	4	2002/0162540 A1	11/07/2002	MATTHEWS et al.
	5	5,884,603	03/23/1999	MATSUKI
	6	2001/0013330 A1	08/16/2001	GRIZZLE et al.

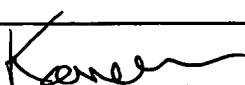

FOREIGN PATENT DOCUMENTS						
Examiner Initials	Cite No.	Document Number	Date	Country	With English Abstract	With English Translation
<div style="font-size: 2em;"> NK J V </div>	7	DE 196 04 737 A1	08/14/1997	GERMANY		
	8	DE 33 34 720 A1	04/04/1985	GERMANY		
	9	JP A 05-272367	10/19/1993	JAPAN	X	X
	10	JP A 07-180575	07/18/1995	JAPAN	X	X
	11	JP A 11-182275	07/06/1999	JAPAN	X	X
	12	JP A 11-350995	12/21/1999	JAPAN	X	X
	13	JP A 05-332172	12/14/1993	JAPAN	X	X
	14	JP A 06-193478	07/12/1994	JAPAN	X	X
	15	JP A 10-103097	04/21/1998	JAPAN	X	X

OTHER DOCUMENTS		
Examiner Initials	Cite No.	(Including Author, Title, Date, Pertinent Pages, etc.)

EXAMINER Kamer	DATE CONSIDERED <div style="font-size: 1.5em;">11/28/07</div>
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Examiner: Initial if citation considered, whether or not citation is in conformance with M.P.E.P. 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Date: March 28, 2006

Form PTO-1449 (REV. 1/06)		US Dept. of Commerce PATENT & TRADEMARK OFFICE		ATTY DOCKET NO. 127243		APPLICATION NO. 10/573,788	
INFORMATION DISCLOSURE STATEMENT (Use several sheets if necessary)				APPLICANT(S) Toshifumi TAKAOKA et al.			
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U.S. PATENT DOCUMENTS							
Examiner Initials	Cite No.	Document Number	Date	Name			
FOREIGN PATENT DOCUMENTS							
Examiner Initials	Cite No.	Document Number	Date	Country	With English Abstract	With English Translation	
NK	1	JP A 2001-164960	06/19/2001	Japan	X	X	
NK	2	JP A 2000-92613	03/31/2000	Japan	X	X	
NK	3	JP A 10-103124	04/21/1998	Japan	X	X	
OTHER DOCUMENTS							
Examiner Initials	Cite No.	(Including Author, Title, Date, Pertinent Pages, etc.)					
EXAMINER				DATE CONSIDERED			
							
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Date: September 11, 2006